# EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
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| | | "20020070738" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:38 |
| | | 250/492.2 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | 250/492.1 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | 250/491.1 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | (electron adj beam) and semiconductor and repair and test | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | "21" and photoresist | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |
| | | "21" and photoresist | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and (electromagnetic or light $1 or laser) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | (electron adj beam) and (remove same residue same beam) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | ("20030132381" \| "20030132765" \| "5162240" \| "5376215" \| "5427052" \| "6306001").PN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |

| | | "20020070738" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
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| | | S57 and "250"/$.ccls. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | S57 and ("324"/$.ccls.) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | (electron adj beam) and (remove same residue same beam) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | S106 and "250"/$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and (electromagnetic or light $1 or laser) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | 250/307 | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
| | | (US-20020070738-$ or US-20020123818-$ or US-20030132765-$ or US-20040018449-$ or US-20040021076-$ or US-20040031932-$ or US-20040167656-$). did. or (US-4417203-$ or US-5412210-$ or US-5543357-$ or US-5637186-$ or US-5866904-$ or US-6005400-$ or US-6124598-$ or US-6150185-$ or US-6232787-$ or US-6323484-$ or US-6407373-$ or US-6451621-$ or US- | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |

| | | 6541770-$ or US-6559662-$ or US-6566655-$ or US-6579733-$ or US-6583414-$ or US-6614050-$ or US-6614244-$ or US-6617087-$ or US-6683308-$ or US-6723987-$ or US-6753194-$ or US-6768324-$ or US-6777677-$ or US-6828554-$).did. | | | | |
| | | 250/310 | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
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| | | ((electron adj beam$1) and (contact adj (hole$1 or opening$1))) and (electromagnetic or light$1 or laser) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:38 |
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| | | "6559662" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | (electron adj beam) and (correction adj process$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |

| | | (electron adj beam) and default and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
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| | | 250/311 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | "20040031932" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
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| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | (electron adj beam) and default and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | S126 or S127 or S128 or S129 or S130 or S131 or S132 or S133 or S134 or S135 or S136 or S137 or S138 or S139 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | "1" or "2" or "3" or "5" or "7" or "9" or "10" or "12" or "13" or "14" or "15" or "16" or "17" or "18" or "19" or "20" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |

| | | ("20030132381" \| "20030132765" \| "5162240" \| "5376215" \| "5427052" \| "6306001").PN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | 324/751 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | (electron adj beam) and semiconductor and fault and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |
| | | (electron adj beam) and semiconductor and repair and test | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |
| | | 324/751 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | 324/537 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | 250/492.22 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |

| | | 250/492.21 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | S204 S205 and (current same (sample or wafer or specimen or target)) and (electron adj beam) and (walls or sidewalls or sides) | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
| | | 250/307 | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
| | | S201 S202 | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
| | | 250/492.21 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | 250/492.2 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | 250/311 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
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| | | 250/310 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | ((electron adj beam$1) and (contact adj (hole$1 or opening$1))) and (electromagnetic or light$1 or laser) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:38 |
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| | | (electron adj beam) and semiconductor and fault and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |

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| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and (yamada.in.) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | 324/522 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | 324/500 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | (electron adj beam) and (correction adj process$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
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| | | S140 and photoresist | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | "20030146381" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |
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| | | S204 S205 and ((current same (sample or wafer or specimen or target)) and (electron adj beam) and (walls or sidewalls or sides)) | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
| | | "kadyshevitch.in." | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | S140 and ("324"/$. ccls.) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | S97 or S98 or S99 or S95 or S96 or S100 or S101 or S102 or S103 or S104 or S105 or S106 or S107 or S108 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | S57 and photoresist | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | S43 or S44 or S45 or S46 or S47 or S48 or S49 or S50 or S51 or S52 or S53 or S54 or S55 or S56 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | ((electron adj beam$1) and (contact adj (hole$1 or opening$1))) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | (electron adj beam) and semiconductor and fault and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | (electron adj beam) and semiconductor and repair and test | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |

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| | | S137 and "250"/$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
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| | | S140 and "250"/$.ccls. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | 324/522 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | 250/491.1 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | S54 and "250"/$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |
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| | | (electron adj beam) and (correction adj process$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |

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| | | "20030146381" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
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| | | "20040031932" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |

| | | (electron adj beam) and semiconductor and repair and test | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | 324/501 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
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| | | kadyshevitch.in. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | "20030146381" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | S39 and "250"/$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |
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| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
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| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and (yamada.in.) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:38 |
| | | S204 S205 and (current same (sample or wafer or specimen or target)) | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
| | | 250/310 | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
| | | S204 S205 and (current same (sample or wafer or specimen or target)) and (electron adj beam) | US-PGPUB; USPAT | OR | ON | 2008/08/26 17:39 |
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| | | S106 and "250"/$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |

| | | (electron adj beam) and (correction adj process$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
|---|---|---|---|---|---|---|
| | | S23 or S24 or S29 or S30 or S31 or S32 or S34 or S35 or S36 or S37 or S38 or S39 or S40 or S41 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | ("20030132381" \| "20030132765" \| "5162240" \| "5376215" \| "5427052" \| "6306001").PN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:38 |
| | | "21" and photoresist | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | 250/492.1 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | "kadyshevitch.in", | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | 250/492.22 | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | ("20030132381" \| "20030132765" \| "5162240" \| "5376215" \| "5427052" \| "6306001").PN. | US-PGPUB; USPAT; USOCR | OR | ON | 2008/08/26 17:39 |
| | | (electron adj beam) and semiconductor and fault and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and (electromagnetic or light $1 or laser) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | (electron adj beam) and (remove same residue same beam) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |

| | | "20030146381" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |
|---|---|---|---|---|---|---|
| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and (electromagnetic or light $1 or laser) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:38 |
| | | S89 and "250"/$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | (electron adj beam) and (correction adj process$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | (electron adj beam) and default and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | (electron adj beam) and semiconductor and fault and correction | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:39 |
| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and (electromagnetic or light $1 or laser) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | ((electron adj beam$1) and (contact adj (hole $1 or opening$1))) and auger | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | "6559662" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/08/26 17:39 |
| | | "1" or "2" or "3" or "5" or "7" or "9" or "10" or "12" or "13" or "14" or "15" or "16" or "17" or "18" or "19" or "20" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/08/26 17:38 |

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